

LT - SPM

Low Temperature Scanning Probe Microscope



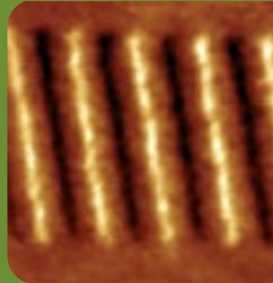
NANOMAGNETICS
INSTRUMENTS



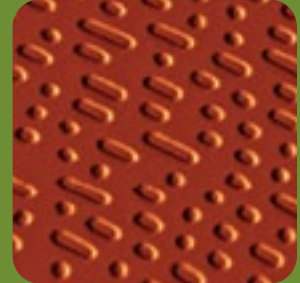
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MFM Image of
Hard Disk, 77 K



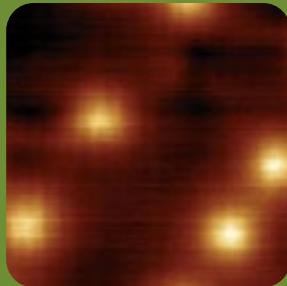
AFM Image of
DVD Surface, 4.2 K



STM Image of
Gold on Mica, 77 K



Vortices in BSCCO, 77 K



AFM (Phase) Image of
Calibration Grating, 4.2 K



SHPM Image of
NIST Calibration Sample, 77 K



System Specifications

Imaging Modes : SHPM, STM, AFM, MFM, EFM, SNOM (in development)

Scan Size Head	Large Area Scan Head	Standart Scan Head	Small Area Scan
	150 x 150 μm @ 300 K	52 x 52 μm @ 300K	8 x 8 μm @ 300 K
	36 x 36 μm @ 77 K	14 x 14 μm @ 77 K	3.5 x 3.5 μm @ 77 K
	18 x 18 μm @ 4.2 K	6 x 6 μm @ 4.2 K	1.5 x 1.5 μm @ 4.2 K

Z Range	Large Area Scan Head	Standart Scan Head	Small Area Scan
	7.0 μm @ 300 K	4.8 μm @ 300 K	2.4 μm @ 300 K
	1.8 μm @ 77 K	1.2 μm @ 77 K	0.6 μm @ 77K
	0.8 μm @ 4.2 K	0.5 μm @ 4.2 K	0.25 μm @ 4.2K

Head Dimensions : 23.6 mm OD x 125 mm or 25.4 mm OD x 100 mm

Sample Approach : Stick-slip type; 10 mm Z, Φ 3 mm XY range with 50 - 800 nm step size

Sample Size : 15 x 15 x 5 mm maximum

Temperature Range : 1.0 K - 300 K (Limited by the cryogenic equipment)

Magnetic Field : >16 T

Suitable cryostats are also available
Software upgrades are free for lifetime

Note: Specifications are subject to change without notice.

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